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DAC8814

SBAS338-JANUARY 2005

Quad, Serial Input 16-Bit Multiplying Digital-to-Analog Converter

FEATURES

- Relative Accuracy: 1 LSB Max
- Differential Nonlinearity: 1 LSB Max
- 2-mA Full-Scale Current \pm 20%, with V_{REF} = \pm 10 V
- 0.5 µs Settling Time

TEXAS

NSTRUMENTS

- Midscale or Zero-Scale Reset
- Four Separate 4Q Multiplying Reference
 Inputs
- Reference Bandwidth: 10 MHz
- Reference Dynamics: -105 dB THD
- SPI™-Compatible 3-Wire Interface: 50 MHz
- Double Buffered Registers Enable
- Simultaneous Multichannel Change
- Internal Power On Reset
- Industry-standard Pin Configuration

APPLICATIONS

- Automatic Test Equipment
- Instrumentation
- Digitally Controlled Calibration

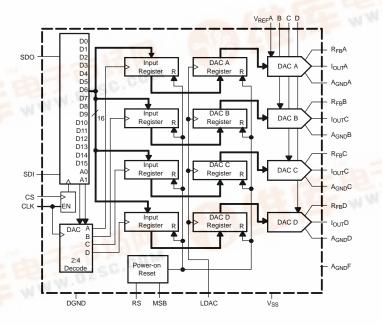
DESCRIPTION

The DAC8814 is a quad, 16-bit, current-output digital-to-analog converter (DAC) designed to operate from a single +2.7 V to 5.0 V supply.

The applied external reference input voltage V_{REF} determines the full-scale output current. An internal feedback resistor (R_{FB}) provides temperature tracking for the full-scale output when combined with an external I-to-V precision amplifier.

A doubled buffered serial data interface offers high-speed, 3-wire, SPI and microcontroller compatible inputs using serial data in (SDI), clock (CLK), and a chip-select (\overline{CS}). In addition, a serial data out pin (SDO) allows for daisy-chaining when multiple packages are used. A common level-sensitive load DAC strobe (LDAC) input allows simultaneous update of all DAC outputs from previously loaded input registers. Additionally, an internal power on reset forces the output voltage to zero at system turn on. An MSB pin allows system reset assertion (\overline{RS}) to force all registers to zero code when MSB = 0, or to half-scale code when MSB = 1.

The DAC8814 is available in an SSOP package.

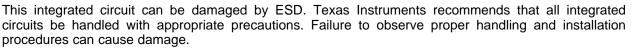


PPPlease be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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DAC8814

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ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

PRODUCT	MINIMUM RELATIVE ACCURACY (LSB)	DIFFERENTIAL NONLINEARITY (LSB)	SPECIFIED TEMPERATURE RANGE	PACKAGE- LEAD	PACKAGE DESIGNATOR	ORDERING NUMBER	TRANSPORT MEDIA, QUANTITY		
DAC8814C	±1			±1	-40°C to +85°C	SSOP-28	DB	DAC8814ICDBT	Tape and Reel, 250
DAC 0014C	ΞI	ΞI	-40 C 10 +65 C	330F-20	DB	DAC8814ICDBR	Tape and Reel, 2500		
DAC8814B	±4	±1.5	-40°C to +85°C	SSOP-28	DB	DAC8814IBDBT	Tape and Reel, 250		
DAC0014D	<u>±</u> 4	±1.5	-40 C 10 +65 C	330F-20	DB	DAC8814IBDBR	Tape and Reel, 2500		

PACKAGE/ORDERING INFORMATION⁽¹⁾

(1) For the most current specifications and package information, see the Package Option Addendum located at the end of this data sheet or refer to our web site at www.ti.com.

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

		DAC8814	UNIT
V _{DD} to GND		-0.3 to +8	V
V _{SS} to GND		-0.3 to -7	V
V _{REF} to GND		-18 to +18	V
Logic inputs and output to	o GND	-0.3 to + 8	V
V(I _{OUT}) to GND		-0.3 to V _{DD} + 0.3	V
A _{GND} X to DGND		-0.3 to +0.3	V
Input current to any pin e	xcept supplies	±50	mA
Package power dissipation	on	(T _J max - T _A)/θ _{JA}	
Thermal resistance, θ_{JA}	28-Lead shrink surface-mount (RS-28)	100	°C/W
Maximum junction tempe	rature (T _J max)	150	°C
Operating temperature ra	ange, Model A	-40 to +85	°C
Storage temperature range	ge	-65 to + 150	°C
Lead temperature	RS-28 (Vapor phase 60s)	215	°C
	RS-28 (Infrared 15s)	220	°C

(1) Stresses above those listed under absolute maximum ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum conditions for extended periods may affect device reliability.



ELECTRICAL CHARACTERISTICS⁽¹⁾

 V_{DD} = 2.7 V to 5.0 V ±10%; V_{SS} = 0 V, $I_{OUT}X$ = Virtual GND, $A_{GND}X$ = 0 V, $V_{REF}A$, B, C, D = 10 V, T_A = full operating temperature range, unless otherwise noted.

			DA	C8814		
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNIT
STATIC PERFORMANCE ⁽²⁾						
Resolution					16	Bits
Relative accuracy	INL	DAC8814B			±4	LSB
	INL	DAC8814C			±1	LSB
Differential nonlinearity	DNL	DAC8814B			±1.5	LSB
	DNL	DAC8814C			±1	LSB
Output leakage current	I _{OUT} X	Data = 0000h, T _A = 25°C			10	nA
	I _{OUT} X	Data = 0000h, $T_A = T_A max$			20	nA
Full-scale gain error	G _{FSE}	Data = FFFFh	±	0.75	±3	mV
Full-scale tempco ⁽³⁾	TCV _{FS}			1		ppm/°C
Feedback resistor	R _{FB} X	$V_{DD} = 5 V$		5		kΩ
REFERENCE INPUT						
V _{REF} X Range	V _{REF} X		-15		15	V
Input resistance	R _{REF} X		4	6	8	kΩ
Input resistance match	R _{REF} X	Channel-to-channel		1		%
Input capacitance ⁽³⁾	C _{REF} X			5		pF
ANALOG OUTPUT						
Output current	I _{OUT} X	Data = FFFFh	1.25		2.5	mA
Output capacitance ⁽³⁾	C _{OUT} X	Code-dependent		80		pF
LOGIC INPUTS AND OUTPU						
Input low voltage	V _{IL}	V _{DD} = +2.7 V			0.6	V
	V _{IL}	$V_{DD} = +5 V$			0.8	V
Input high voltage	V _{IH}	V _{DD} = +2.7 V	2.1			V
	V _{IH}	$V_{DD} = +5 V$	2.4			V
Input leakage current	IIL				1	μA
Input capacitance ⁽³⁾	C _{IL}				10	pF
Logic output low voltage	V _{OL}	I _{OL} = 1.6 mA			0.4	V
Logic output high voltage	V _{OH}	I _{OH} = 100 μA	4			V
INTERFACE TIMING ⁽³⁾ , ⁽⁴⁾						
Clock width high	t _{CH}		25			ns
Clock width low	t _{CL}		25			ns
CS to Clock setup	t _{CSS}		0			ns
Clock to CS hold	t _{CSH}		25			ns
Clock to SDO prop delay	t _{PD}		2		20	ns
Load DAC pulsewidth	t _{LDAC}		25			ns
Data setup	t _{DS}		20			ns
Data hold	t _{DH}		20			ns
Load setup	t _{LDS}		5			ns
Load hold	t _{LDH}		25			ns

Specifications subject to change without notice. (1)

All static performance tests (except I_{OUT}) are performed in a closed-loop system using an external precision OPA277 I-to-V converter amplifier. The DAC8814 R_{FB} terminal is tied to the amplifier output. Typical values represent average readings measured at +25°C. These parameters are specified by design and not subject to production testing. All input control signals are specified with t_R = t_F = 2.5 ns (10% to 90% of 3 V) and timed from a voltage level of 1.5 V. (2) (3)

⁽⁴⁾



ELECTRICAL CHARACTERISTICS (continued)

 V_{DD} = 2.7 V to 5.0 V ±10%; V_{SS} = 0 V, $I_{OUT}X$ = Virtual GND, $A_{GND}X$ = 0 V, $V_{REF}A$, B, C, D = 10 V, T_A = full operating temperature range, unless otherwise noted.

			D			
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY CHARACTERISTICS	5					
Power supply range	V _{DD RANGE}		2.7		5.5	V
Positive supply current	I _{DD}	Logic inputs = 0 V		2	5	μA
	I _{DD}	V _{DD} = +4.5 V to +5.5 V		2	5	μA
	I _{DD}	V _{DD} = +2.7 V to +3.6 V		1	2.5	μA
Negative supply current	I _{SS}	Logic inputs = 0 V, V_{SS} = -5 V		0.001	1	μA
Power dissipation	P _{DISS}	Logic inputs = 0 V			0.0275	mW
Power supply sensitivity	P _{SS}	$\Delta V_{DD} = \pm 5\%$			0.006	%
AC CHARACTERISTICS ⁽⁵⁾						
Output voltage settling time	t _s	To $\pm 0.1\%$ of full-scale, Data = 0000h to FFFFh to 0000h		0.5		μs
	t _s	To $\pm 0.0051\%$ of full-scale, Data = 0000h to FFFFh to 0000h		1		μs
Reference multiplying BW	BW -3 dB	$V_{REF}X = 100 \text{ mV}_{RMS}$, Data = FFFF _H , C _{FB} = 15 pF		10		MHz
DAC glitch impulse	Q	V _{REF} X = 10 V, Data = 0000h to 8000h to 0000h		1		nV/s
Feedthrough error	V _{OUT} X/V _{REF} X	Data = 0000h, V _{REF} X = 100 mV _{RMS} , f = 100 kHz		-70		dB
Crosstalk error	V _{OUT} A/V _{REF} B	Data = 0000h, V _{REF} B = 100 mV _{RMS} , Adjacent channel, f = 100 kHz		-90		dB
Digital feedthrough	Q	\overline{CS} = 1 and f_{CLK} = 1 MHz		2		nV/s
Total harmonic distortion	THD	$V_{REF} = 5 V_{PP}$, Data = FFFFh, f = 1 kHz		-105		dB
Output spot noise voltage	en	f = 1 kHz, BW = 1 Hz		12		nV/√Hz

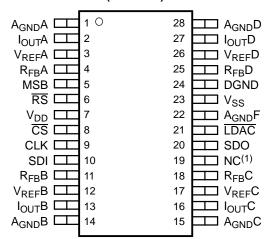
(5) All ac characteristic tests are performed in a closed-loop system using an OPA627 I-to-V converter amplifier.

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PIN CONFIGURATIONS

DAC8814 (TOP VIEW)



NOTE (1): NC - No internal connection

PIN DESCRIPTION

PIN	NAME	DESCRIPTION						
1, 14, 15, 28	$A_{GND}A$, $A_{GND}B$, $A_{GND}C$, $A_{GND}D$	DAC A, B, C, D Analog ground.						
2, 13, 16, 27	I _{OUT} A, I _{OUT} B, I _{OUT} C, I _{OUT} D	DAC A, B, C, D Current output.						
3, 12, 17, 26	$V_{REF}A$, $V_{REF}B$, $V_{REF}C$, $V_{REF}D$	DAC A, B, C, D Reference voltage input terminal. Establishes DAC A, B, C, D full-scale output voltage. Can be tied to V_{DD} .						
4, 11, 18, 25	R _{FB} A, R _{FB} B, R _{FB} C, R _{FB} D	Establish voltage output for DAC A, B, C, D by connecting to external amplifier output.						
5	MSB	MSB Bit set during a reset pulse (RS) or at system power on if tied to ground or V_{DD} .						
6	RS	Reset pin, active low. Input register and DAC registers are set to all zeros or half scale code (8000h) determined by the voltage on the MSB pin. Register data = 8000h when MSB = 1.						
7	V _{DD}	Positive power supply input. Specified range of operation 5 V $\pm 10\%$.						
8	CS	Chip-select; active low input. Disables shift register loading when high. Transfers shift register data to input register when CS/LDAC goes high. Does not affect LDAC operation.						
9	CLK	Clock input; positive edge triggered clocks data into shift register						
10	SDI	Serial data input; data loads directly into the shift register.						
19	NC	Not connected; leave floating.						
20	SDO	Serial data output; input data loads directly into shift register. Data appears at SDO, 19 clock pulses after input at the SDI pin.						
21	LDAC	Load DAC register strobe; level sensitive active low. Tranfers all input register data to the DAC registers. Asynchronous active low input. See Table 1 for operation.						
22	A _{GND} F	High current analog force ground.						
23	V _{SS}	Negative bias power-supply input. Specified range of operation -0.3 V to -5.5 V.						
24	DGND	Digital ground.						



TYPICAL CHARACTERISTICS: V_{DD} = +5 V

At $T_A = +25^{\circ}C$, $+V_{DD} = +5$ V, unless otherwise noted.

Channel A

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 1.

LINEARITY ERROR vs DIGITAL INPUT CODE Figure 2.

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic

Forthcoming

Graphic Forthcoming

Figure 3.

Figure 4.



TYPICAL CHARACTERISTICS: V_{DD} = +5 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +5$ V, unless otherwise noted.

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 5.

Figure 6.



TYPICAL CHARACTERISTICS: V_{DD} = +5 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +5$ V, unless otherwise noted.

Channel B

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 7.

LINEARITY ERROR vs DIGITAL INPUT CODE DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 8.

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 9.

Graphic Forthcoming

Figure 10.



TYPICAL CHARACTERISTICS: V_{DD} = +5 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +5$ V, unless otherwise noted.

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 11.

Figure 12.



TYPICAL CHARACTERISTICS: V_{DD} = +5 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +5$ V, unless otherwise noted.

Channel C

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 13.

LINEARITY ERROR vs DIGITAL INPUT CODE DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 14.

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 15.

Graphic Forthcoming

Figure 16.



TYPICAL CHARACTERISTICS: V_{DD} = +5 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +5$ V, unless otherwise noted.

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 17.

Figure 18.



TYPICAL CHARACTERISTICS: V_{DD} = +5 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +5$ V, unless otherwise noted.

Channel D

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 19.

LINEARITY ERROR vs DIGITAL INPUT CODE DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 20.

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 21.

Graphic

Forthcoming

Figure 22.



TYPICAL CHARACTERISTICS: V_{DD} = +5 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +5$ V, unless otherwise noted.

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

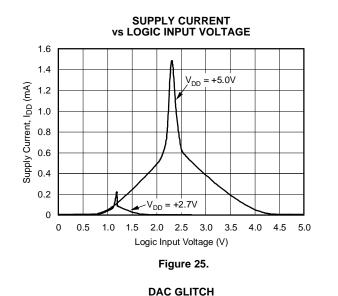
Figure 23.

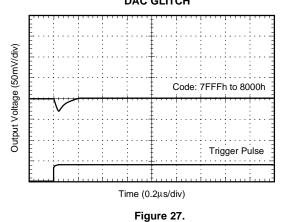
Figure 24.



TYPICAL CHARACTERISTICS: V_{DD} = +5 V (continued)

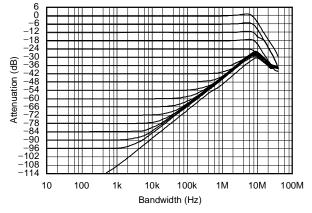
At $T_A = +25^{\circ}C$, $+V_{DD} = +5$ V, unless otherwise noted.





PRODUCT PREVIEW

REFERENCE MULTIPLYING BANDWIDTH





DAC SETTLING TIME

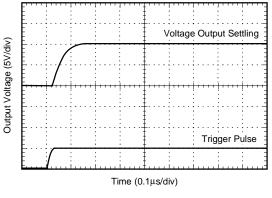


Figure 28.



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TYPICAL CHARACTERISTICS: $V_{DD} = +2.7 V$

At $T_A = +25^{\circ}C$, $+V_{DD} = +2.7$ V, unless otherwise noted.

Channel A

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 29.

LINEARITY ERROR vs DIGITAL INPUT CODE Figure 30.

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 31.

Graphic Forthcoming

Figure 32.



TYPICAL CHARACTERISTICS: V_{DD} = +2.7 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +2.7$ V, unless otherwise noted.

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 33.

Figure 34.



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TYPICAL CHARACTERISTICS: V_{DD} = +2.7 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +2.7$ V, unless otherwise noted.

Channel B

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 35.

LINEARITY ERROR vs DIGITAL INPUT CODE Figure 36.

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 37.

Graphic Forthcoming

Figure 38.



TYPICAL CHARACTERISTICS: V_{DD} = +2.7 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +2.7$ V, unless otherwise noted.

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 39.

Figure 40.



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TYPICAL CHARACTERISTICS: V_{DD} = +2.7 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +2.7$ V, unless otherwise noted.

Channel C

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 41.

LINEARITY ERROR vs DIGITAL INPUT CODE DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 42.

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 43.

Graphic Forthcoming

Figure 44.



TYPICAL CHARACTERISTICS: V_{DD} = +2.7 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +2.7$ V, unless otherwise noted.

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 45.

Figure 46.



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TYPICAL CHARACTERISTICS: V_{DD} = +2.7 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +2.7$ V, unless otherwise noted.

Channel D

LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 47.

LINEARITY ERROR vs DIGITAL INPUT CODE Figure 48.

DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE

Graphic Forthcoming

Figure 49.

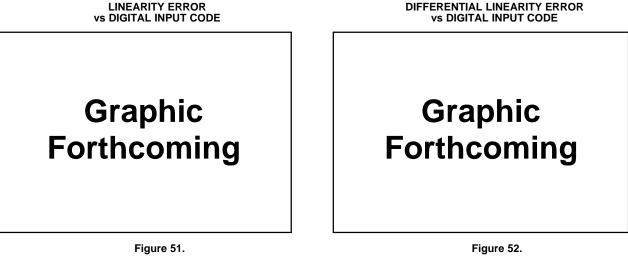
Graphic Forthcoming

Figure 50.



TYPICAL CHARACTERISTICS: V_{DD} = +2.7 V (continued)

At $T_A = +25^{\circ}C$, $+V_{DD} = +2.7$ V, unless otherwise noted.



PARAMETER MEASUREMENT INFORMATION D1 SDI A0 D15 D14 D13 D13 D12 D11 D10 D0 CLK Input REG. LD t_{CSS} t_{csh} t_{ds} t_{dh} t_{cl} cs t_{lds} t_{pď} LDAC **t**LDH t_{LDAC} -SDO

Figure 53. DAC8814 Timing Diagram

THEORY OF OPERATION

CIRCUIT OPERATION

The DAC8814 contains four, 16-bit, current-output, digital-to-analog converters (DACs) respectively. Each DAC has its own independent multiplying reference input. The DAC8814 uses a 3-wire SPI compatible serial data interface, with a configurable asynchronous \overline{RS} pin for half-scale (MSB = 1) or zero-scale (MSB = 0) preset. In addition, an LDAC strobe enables four channel simultaneous updates for hardware synchronized output voltage changes.

D/A Converter

The DAC8814 contains four current-steering R-2R ladder DACs. Figure 54 shows a typical equivalent DAC. Each DAC contains a matching feedback resistor for use with an external I-to-V converter amplifier. The $R_{FB}X$ pin is connected to the output of the external amplifier. The $I_{OUT}X$ terminal is connected to the inverting input of the external amplifier. The $A_{GND}X$ pin should be Kelvin-connected to the load point in the circuit requiring the full 16-bit accuracy.

TEXAS INSTRUMENTS www.ti.com

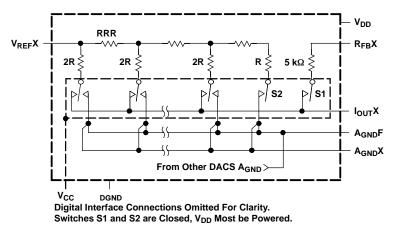
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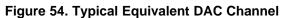
The DAC is designed to operate with both negative or positive reference voltages. The V_{DD} power pin is only used by the logic to drive the DAC switches on and off. Note that a matching switch is used in series with the internal 5 k Ω feedback resistor. If users are attempting to measure the value of R_{FB}, power must be applied to V_{DD} in order to achieve continuity. An additional V_{SS} bias pin is used to guard the substrate during high temperature applications to minimize zero-scale leakage currents that double every 10°C. The DAC output voltage is determined by V_{REF} and the digital data (D) according to Equation 1:

$$V_{OUT} = -V_{REF} \times \frac{D}{65536}$$

(1)

Note that the output polarity is opposite of the V_{REF} polarity for dc reference voltages.





The DAC is also designed to accommodate ac reference input signals. The DAC8814 accommodates input reference voltages in the range of -12 V to +12 V. The reference voltage inputs exhibit a constant nominal input resistance of 5 k Ω , \pm 30%. On the other hand, the DAC outputs I_{OUT}A, B, C, D are code-dependent and produce various output resistances and capacitances.

The choice of external amplifier should take into account the variation in impedance generated by the DAC8814 on the amplifiers' inverting input node. The feedback resistance, in parallel with the DAC ladder resistance, dominates output voltage noise. For multiplying mode applications, an external feedback compensation capacitor (C_{FB}) may be needed to provide a critically damped output response for step changes in reference input voltages.

Figure 26 shows the gain vs frequency performance at various attenuation settings using a 23 pF external feedback capacitor connected across the $I_{OUT}X$ and $R_{FB}X$ terminals. In order to maintain good analog performance, power supply bypassing of 0.01 µF, in parallel with 1 µF, is recommended. Under these conditions, clean power supply with low ripple voltage capability should be used. Switching power supplies is usually not suitable for this application due to the higher ripple voltage and P_{SS} frequency-dependent characteristics. It is best to derive the DAC8814 5-V supply from the system analog supply voltages. (Do not use the digital 5-V supply.) See Figure 55.



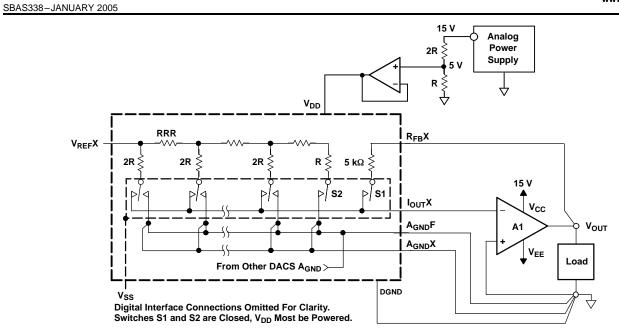
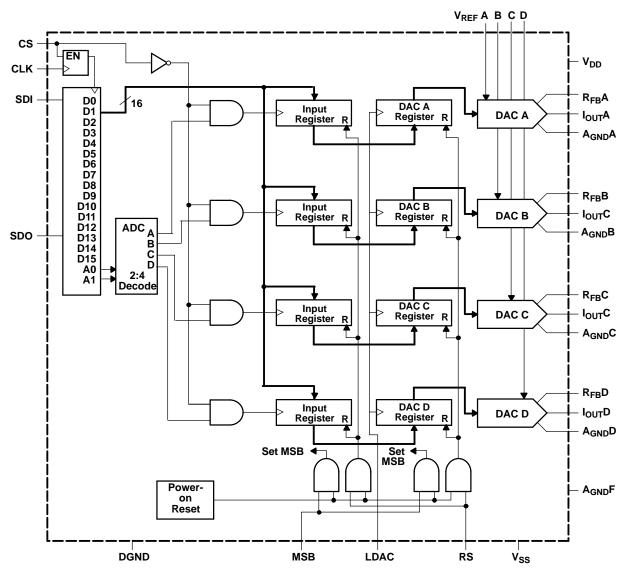


Figure 55. Recommended Kelvin-Sensed Hookup

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SERIAL DATA INTERFACE

The DAC8814 uses a 3-wire (\overline{CS} , SDI, CLK) SPI-compatible serial data interface. Serial data of the DAC8814 is clocked into the serial input register in an 16-bit data-word format. MSB bits are loaded first. Table 2 defines the 16 data-word bits for the DAC8814.

Data is placed on the SDI pin, and clocked into the register on the positive clock edge of CLK subject to the data setup and data hold time requirements specified in the Interface Timing Specifications. Data can only be clocked in while the \overline{CS} chip select pin is active low. For the DAC8814, only the last 16 bits clocked into the serial register are interrogated when the \overline{CS} pin returns to the logic high state.

Since most microcontrollers output serial data in 8-bit bytes, three right-justified data bytes can be written to the DAC8814. Keeping the \overline{CS} line low between the first, second, and third byte transfers results in a successful serial register update. Similarly, two right-justified data bytes can be written to the DAC8814. Keeping the \overline{CS} line low between the first and second byte transfer will result in a successful serial register update.



Once the data is properly aligned in the shift register, the positive edge of the \overline{CS} initiates the transfer of new data to the target DAC register, determined by the decoding of address bits A1and A0. For the DAC8814, Table 1, Table 2, Table 3 and Figure 53 define the characteristics of the software serial interface. Figure 57 shows the equivalent logic interface for the key digital control pins for the DAC8814.

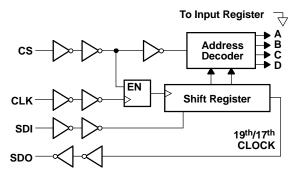


Figure 57. DAC8814 Equivalent Logic Interface

Two additional pins \overline{RS} and MSB provide hardware control over the preset function and DAC register loading. If these functions are not needed, the \overline{RS} pin can be tied to logic high. The asynchronous input \overline{RS} pin forces all input and DAC registers to either the zero-code state (MSB = 0), or the half-scale state (MSB = 1).

POWER ON RESET

When the V_{DD} power supply is turned on, an internal reset strobe forces all the Input and DAC registers to the zero-code state or half-scale, depending on the MSB pin voltage. The V_{DD} power supply should have a smooth positive ramp without drooping in order to have consistent results, especially in the region of V_{DD} = 1.5 V to 2.3 V. The V_{SS} supply has no effect on the power-on reset performance. The DAC register data stays at zero or half-scale setting until a valid serial register data load takes place.

ESD Protection Circuits

All logic-input pins contain back-biased ESD protection zener diodes connected to ground (DGND) and V_{DD} as shown in Figure 58.

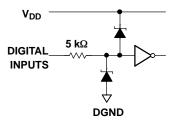


Figure 58. Equivalent ESD Protection Circuits



PCB LAYOUT

In printed circuit board (PCB) layout, all analog ground A_{GND}X should be tied together.

CS	CLK	LDAC	RS	MSB	SERIAL SHIFT REGISTER	INPUT REGISTER	DAC REGISTER
н	Х	Н	Н	Х	No effect	Latched	Latched
L	L	Н	Н	Х	No effect	Latched	Latched
L	↑+	Н	Н	Х	Shift register data advanced one bit	Latched	Latched
L	Н	Н	Н	Х	No effect	Latched	Latched
↑+	L	Н	Н	х	No effect	Selected DAC updated with current SR con- tents	Latched
н	Х	L	Н	Х	No effect	Latched	Transparent
н	Х	Н	Н	Х	No effect	Latched	Latched
н	Х	^+	Н	Х	No effect	Latched	Latched
Н	Х	Н	L	0	No effect	Latched data = 0000h	Latched data = 0000h
Х	↑+	Н	L	Н	No effect	Latched data = 8000h	Latched data = 8000h

Table 1. Control Logic Truth Table⁽¹⁾

(1) \uparrow = Positive logic transition; **X** = Do not care

Table 2. Serial Input Register Data Format, Data Loaded MSB First⁽¹⁾

Bit	B17 (MSB)	B16	B15	B14	B13	B12	B11	B10	B9	B8	B7	B6	B5	B4	B3	B2	B1	B0 (LSB)
Dat	a A1	A0	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0

(1) Only the last 18 bits of data clocked into the serial register (address + data) are inspected when the CS line positive edge returns to logic high. At this point an internally-generated load strobe transfers the serial register data contents (bits D15-D0) to the decoded DAC-input-register address determined by bits A1 and A0. Any extra bits clocked into the DAC8814 shift register are ignored, only the last 18 bits clocked in are used. If double-buffered data is not needed, the LDAC pin can be tied logic low to disable the DAC registers.

A1	A0	DAC DECODE
0	0	DAC A
0	1	DAC B
1	0	DAC C
1	1	DAC D

Table 3. Address Decode

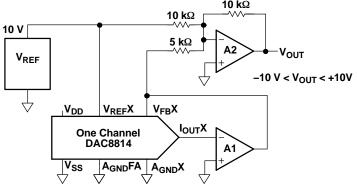


APPLICATION INFORMATION

The DAC8814, a 2-quadrant multiplying DAC, can be used to generate a unipolar output. The polarity of the full-scale output I_{OUT} is the inverse of the input reference voltage at V_{REF} .

Some applications require full 4-quadrant multiplying capabilities or bipolar output swing, as shown in Figure 59. An additional external op amp A2 is added as a summing amp. In this circuit the first and second amps (A1 and A2) provide a gain of 2X that widens the output span to 20 V. A 4-quadrant multiplying circuit is implemented by using a 10-V offset of the reference voltage to bias A2. According to the following circuit transfer equation (Equation 2), input data (D) from code 0 to full scale produces output voltages of $V_{OUT} = -10$ V to $V_{OUT} = 10$ V.

$$V_{OUT} = \left(\frac{D}{32,768} - 1\right) \times V_{REF}$$
(2)



Digital Interface Connections Omitted For Clarity.

Figure 59. Four-Quadrant Multiplying Application Circuit

Cross-Reference

The DAC8814 has an industry-standard pinout. Table 4 provides the cross-reference information.

PRODUCT	INL (LSB)	DNL (LSB)	SPECIFIED TEMPERATURE RANGE	PACKAGE DESCRIPTION	PACKAGE OPTION	CROSS- REFERENCE PART
DAC8814ICDB	±1	±1	-40°C to +85°C	28-Lead MicroSOIC	SSOP-28	N/A
DAC8814IBDB	±4	±1.5	-40°C to +85°C	28-Lead MicroSOIC	SSOP-28	AD5544RS

Table 4. Cross-Reference



30-Mar-2005

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
DAC8814IBDBR	PREVIEW	SSOP	DB	28	2500	TBD	Call TI	Call TI
DAC8814IBDBT	PREVIEW	SSOP	DB	28	250	TBD	Call TI	Call TI
DAC8814ICDBR	PREVIEW	SSOP	DB	28	2500	TBD	Call TI	Call TI
DAC8814ICDBT	PREVIEW	SSOP	DB	28	250	TBD	Call TI	Call TI

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS) or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details. TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

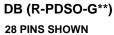
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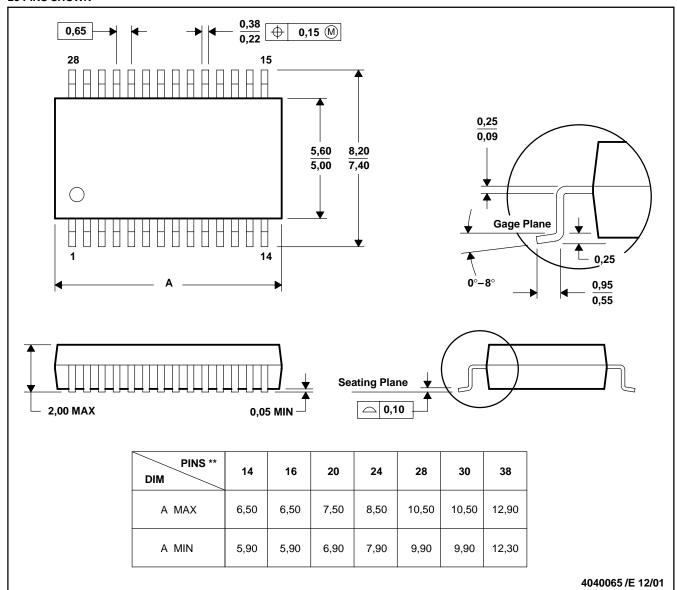
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MECHANICAL DATA

MSSO002E - JANUARY 1995 - REVISED DECEMBER 2001

PLASTIC SMALL-OUTLINE





NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-150



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